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(71) Applicant: JEOL LTD  
NIPPON DENSHI KURIEITEIBU  
KK  
(72) Inventor: SAKAI SHIGEYASU  
HIGO KATSURO  
YOSHIMURA MASAOKI

## (54) PRODUCT INSPECTING APPARATUS WITH THERMOGRAPHY

## (57) Abstract:

**PROBLEM TO BE SOLVED:** To improve accuracy in detecting failures of a heat-sealed product having a temperature distribution including a high temperature region and a low temperature region by acquiring detection signals of an infrared camera in a predetermined measurement range in a direction for carrying, counting signals at an abnormal temperature level while comparing with a determination value at the abnormal temperature level and comparing the count with a determination value of a defective product.

**SOLUTION:** An infrared camera 12 line-scans objects to be inspected which have been heat-sealed and cut into a product unit by a heat-sealer 11 for outputting a temperature measurement signal  $t_m$ , and the temperature measurement signal  $t_m$  is compared in a level determination part 14 with determination values  $T_A$ ,  $T_B$ ,  $T_C$  stored in a determination value register 18 for de-

termining a level. Respective temperature measurement signals  $t_m$  whose level have been determined are counted by a level counting part 15, and the respective counts  $n_A$ ,  $n_B$ ,  $n_C$  are held in a counter 19. A defective product determination part 16 compares the counts  $n_A$ ,  $n_B$ ,  $n_C$  counted by the level counting part 15 with the respective determination values  $T_A$ ,  $T_B$ ,  $T_C$  stored in a determination value register 20 for determining defective product. Determination signals are sent to a product processor 13.

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